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Integrated circuit – EMC evaluation of transceivers –
Part 6: PSI5 transceivers

Circuits intégrés – Évaluation de la CEM des émetteurs-récepteurs –
Partie 6: Émetteurs-récepteurs PSI5

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INTEGRATED CIRCUIT –
EMC EVALUATION OF TRANSCEIVERS –

Part 6: PSI5 transceivers

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Draft	Report on voting
47A/1145/FDIS	47A/1147/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

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INTEGRATED CIRCUIT –
EMC EVALUATION OF TRANSCEIVERS –

Part 6: PSI5 transceivers

1 Scope

This part of IEC 62228 specifies test and measurement methods for EMC evaluation of peripheral sensor interface 5 (PSI5) transceiver integrated circuits (ICs) under network condition. It defines test configurations, test conditions, test signals, failure criteria, test procedures, test setups and test boards. It is applicable for PSI5 satellite ICs (e.g. sensors) and ICs with embedded PSI5 transceivers (e.g. PSI5 electronic control unit IC). This document covers

- the emission of RF disturbances,
- the immunity against RF disturbances,
- the immunity against impulses, and
- the immunity against electrostatic discharges (ESD).

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 61967-1, *Integrated circuits – Measurement of electromagnetic emissions – Part 1: General conditions and definitions*

IEC 61967-4, *Integrated circuits – Measurement of electromagnetic emissions – Part 4: Measurement of conducted emissions – 1 Ω / 150 Ω direct coupling method*

IEC 62132-1, *Integrated circuits – Measurement of electromagnetic immunity – Part 1: General conditions and definitions*

IEC 62132-4, *Integrated circuits – Measurement of electromagnetic immunity 150 kHz to 1 GHz – Part 4: Direct RF power injection method*

IEC 62215-3, *Integrated circuits – Measurement of impulse immunity – Part 3: Non-synchronous transient injection method*

IEC 62228-1, *Integrated circuits – EMC evaluation of transceivers – Part 1: General conditions and definitions*

ISO 7637-2, *Road vehicles – Electrical disturbances from conduction and coupling – Part 2: Electrical transient conduction along supply lines only*

ISO 10605, *Road vehicles – Test methods for electrical disturbances from electrostatic discharge*

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